### Statistical methods

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### **Contents and resources**

- 1. Probability distributions
- 2. Statistical and systematic uncertainties
- 3. Estimators fitting
- 4. Probability and confidence intervals
- 5. Multivariate techniques will not be covered instead a tutorial
- Statistics R. J. Barlow (John Wiley & Sons)
- A Practical Guide to Data Analysis for Physical Science Students L. Lyons (Cambridge University Press)
- Leo chapter 4
- Data analysis techniques for HEP, Fruhwirth et al (Cambridge University Press)
- Particle Data Group, Review of Particle Properties, Sections 35 and 36
- SLUO lectures on statistics (Frank Porter and Roger Barlow) <u>http://www-group.slac.stanford.edu/sluo/lectures/Stat\_Lectures.html</u>
- RooFit: <u>http://roofit.sourceforge.net/</u>
- RooStats: <u>https://twiki.cern.ch/twiki/bin/view/RooStats/</u>

### Lies, damn lies and statistics Benjamin Disraeli (British politician, 1804-1881)



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## Why you need to know some statistics?

- Most of you will be measuring some parameter during your graduate studies
  - branching fraction
  - mass
  - coupling
  - differential cross section

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In reality you never measure a single value but an interval expressed as

$$R_{DK} = [1.98 \pm 0.62 \pm 0.24] \times 10^{-2}$$
  
Central Statistical Systematic uncertainty uncertainty

[M. Nayak et al., (Belle Collaboration), PRD **88**, 091104]

Which is the <u>most</u> important number?

### You will need

- 1. A method of estimating the central value and its related statistical uncertainty in a **consistent**, **unbiased** and **efficient** way
- 2. To identify sources and estimate the magnitude of the systematic uncertainty
- 3. Combine measurements and uncertainties, even if they are **correlated**
- 4. Interpret your result **degree of belief/confidence** in your result
  - all intervals correspond to some probability
  - $\pm$  one standard deviation should indicate that if you repeat your measurement many times your result will lie in that range 68% of the time
  - Interpret your result

#### Will try to give a flavour of how to go about the above

- But statistical methods are tools, which you must learn to use practically
- 'A bad workman blames his tools'

### Part 1 PROBABILITY DISTRIBUTIONS

### Assumed knowledge/revision I

- Classical definition of probability
  - If I toss an unbiased coin many times the no. of heads divided by number of tosses  $\rightarrow 1/2 \equiv$  Probability of a coin toss giving heads
- Definition of mean and standard deviation for a sample and distributions (discrete and continuous)

Sample: 
$$\overline{x} = \frac{1}{N} \sum x_i$$
  $\sigma = \sqrt{V(x)} = \sqrt{\overline{x^2} - \overline{x}^2}$   
Discrete distribution:  $\langle r \rangle = \sum_r r P(r)$   $\sigma = \sqrt{\langle r^2 \rangle - \langle r \rangle^2}$   
Continuous distribution:  $\langle x \rangle = \int x P(x) dx$   $\sigma = \sqrt{\langle x^2 \rangle - \langle x \rangle^2}$ 

• A probability density function

$$P(x) = \lim_{\delta x \to 0} \frac{\text{Probability result lies between } x \text{ and } x + \delta x}{\delta x}$$

### Assumed knowledge/revision II

• Covariance and correlations

$$V_{ij} = \operatorname{cov}(x_{(i)}, x_{(j)}) = x_{(i)}x_{(j)} - x_{(i)} x_{(j)}$$
  
If  $x_{(i)}$  and  $x_{(j)}$  independent this is zero  
 $V_{ij} = \rho_{ij}\sigma_i\sigma_j$   
where  $\rho_{ij} \in (-1, 1)$  is the correlation coefficient

- Uncorrelated: pp vertex position and jet energy
- Partially correlated: electron energy and momentum
  - why only partially?
- Fully correlated: number of pp collisions and luminosity

### Law of large numbers

- Something we all know but it is worth emphasizing
  - We are always trying to measure some true parameter or distribution
  - However, a few pieces of data are unlikely to give you a good estimate of that parameter/distribution due to the fluctuations
  - Example: tossing a coin four times

No. of Heads	0	1	2	3	4
Probability	1/16	4/16	6/16	4/16	1/16

- Now do the experiment and estimate the probability after
  - 10 tosses
  - 1000 tosses
  - 100000 tosses

### Law of large numbers: example



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### Probability distributions

- We are now going to review four important ones which often describe physical processes of interest
  - Binomial
  - Poisson
  - Gaussian
  - Uniform
- Not exhaustive
  - Multinomial
  - Exponential lifetimes
  - Breit-Wigner/Cauchy resonances
  - Landau dE/dx in a thin piece of material
  - Polynomials particularly orthogonal sets Legendre, Hermite, Chebyshev

• χ<sup>2</sup>

### **Binomial distribution**

- Applies to pass-fail situations
  - Coin toss
  - Event selection
  - Forward-backward asymmetries (or similar)
- From n attempts there 2<sup>n</sup> ways to put together the successes and failures
- The number of ways that contain *r* successes is

Binomial coefficient = 
$$_{n}C_{r} = \frac{n!}{r!(n-r)!}$$

• Therefore, probability of *r* successes from *n* trials is

$$P(r; p, n) = p^{r} (1-p)^{n-r} {}_{n}C_{r}$$

where p is the individual probability of success at each trial

### **Binomial distribution II**

• Check of the total probability

$$\sum_{r=0}^{n} p^{r} (1-p)^{n-r} {}_{n} C_{r} = [p+(1-p)]^{n} = 1$$

Mean and standard deviation

$$\langle r \rangle = pn$$
 and  $\sigma = \sqrt{np(1-p)}$ 

• Example distributions



### Binomial example: efficiencies

- Often you need to estimate a selection efficiency from a sample of simulated events:
  - Efficiency = ε = no. selected (m)/no. in sample (n)
- No. selected follows a binomial distribution
  - Therefore, uncertainty is

$$\sigma_{\varepsilon} = \sqrt{\frac{\varepsilon(1-\varepsilon)}{n}}$$

- Common mistake is to say error is sqrt(m)/n
  - 98% from a sample of 1000 events  $\Rightarrow$ 
    - (98.0±3.1)% (efficiency greater than 100% !)
    - (98.0±0.4)% correct binomial error

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### Poisson

- Describes the a case where there are still particular outcomes like the binomial but you don't know the number of trials
- Sharp events in a continuum of nothing happening
  - Radioactive decay
  - Flashes of lightening
  - Signal produced in a collision
- One knows the average number of events over some period
  - Want to know the probability of observing a given number in a certain period
- Analysis of binomial distribution, in which the number of trials n becomes large while the probability p becomes small but their product is constant
  - On board





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#### Phys. Rev. Lett. 58, 1494–1496 (1987) and Barlow



<b>Νο.</b> ν	0	1	2	3	4	5	6	7	8	9
Intervals	1042	860	307	78	15	3	0	0	0	1
Predict.	1064	823	318	82	16	2	0.3	0.03	0.003	0.0003

Data collected in 10 second intervals on 23<sup>rd</sup> February 1987 around the time of the first observation of SN1987A

Ignoring the interval with nine neutrinos the average is 0.77

The Poisson prediction for  $\lambda$ =0.77 is given which is in excellent agreement with the observed counts

Therefore, probability that the interval with nine events is a fluctuation of the background rate is tiny

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### Gaussian

- The most common distribution there is a reason which we will discuss in the next class
  - Unlike binomial or Poisson it describes a continuous distribution
- Appropriately normalised

$$P(x; \mu, \sigma) = \frac{1}{\sqrt{2\pi\sigma}} \exp\left(-\frac{(x-\mu)^2}{2\sigma^2}\right)$$
$$\langle x \rangle = \mu \text{ and } \sigma = \sigma$$

- Will show in problem set that as n→∞ the Poisson distribution tends toward Gaussian distribution
- Will assume you have used this distribution

## Uniform distribution: parameterizing ignorance?



- Use this if you don't know a value but only the range in which may have fallen with equal probability
  - Binned data
  - A hit on Si strip
  - Some parameter which is bounded i.e. a phase 0-2π
- Self evident that <x>=(a+b)/2
- Standard deviation is (proof

on board)

$$\sigma = \frac{b-a}{\sqrt{12}}$$

#### Part 2 LIVING WITH ERRORS

### **Uncertainties/errors**

- Are everywhere
- Personally I prefer uncertainty/resolution to error, some of your collaborators maybe be religious about this
  - Error suggest you are doing something wrong
  - But by carefully considering your uncertainties you are being righteous
- What we need to know are the different types, how to evaluate them and to combine them
- Otherwise you result can lead to a lot of mischief



### Why are uncertainties Gaussian?

- The Central Limit Theorem is the answer
  - If you take the sum X of N independent variables  $x_i$  , each taken from a distribution of mean  $\mu_i$  and variance  $V_i$  the distribution for X
    - 1. has an expectation value <X> =  $\Sigma \mu_i$
    - 2. has a variance  $V(X) = \sum V_i$  and
    - 3. becomes a Gaussian as  $N \rightarrow \infty$
- I will prove 1 and 2 on the board now
- But the most startling of these 3 requires a more formal definition which I frankly do not have time to do:
  - Appendix 2 Barlow contains a proof
  - However, I recommend Chapter 30 of the 3<sup>rd</sup> Edition of Riley, Hobson and Bence 'Mathematical Methods for Physics and Engineering' to understand moments and hence the proof of the CLT



### Uncertainty on the mean: do more!

- If we make many independent measurements of the same quantity with a true mean  $\boldsymbol{\mu}$ 
  - $\langle X \rangle = \Sigma \mu = N\mu$  (from CLT)
  - Therefore, your estimate of the mean is X/N
  - $V(X) = \Sigma \sigma^2 = N\sigma^2$  (from CLT)
  - Therefore,

$$V(\text{mean}) = \frac{1}{N^2} V(X) = \frac{\sigma^2}{N}$$

- Taking more measurements is good for you
  - But to halve an uncertainty four times more measurements!
  - Only systematic uncertainties can mess this up

### **Combining measurements**

- There are two measurements of the top mass with different resolutions one with (175±2) GeV/c<sup>2</sup> and the other (176±1) GeV/c<sup>2</sup>
  - How do we combine them?

 $\overline{x} =$ 

- I would need four more of the first measurement to get the same precision as the second
- Switch it: second measurement is equivalent to four of the first so should be weighted by a factor 4

• Therefore 
$$\overline{m_t} = \frac{1}{5} \times 175 + \frac{4}{5} \times 176 = 175.8 \text{ GeV}$$
  
Proof in Problem set

 $\sum_{i=1}^{\infty} \frac{x_i}{\sigma_i^2} \text{ and } V(\overline{x}) =$ 

• In general

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### Caveats

#### • CLT

- Works well in the central part of a distribution
  - Core 2 or 3 sigma from the mean
- But the events outside this outliers, tails or wings do not tend to Gaussian as fast
- As N never really tends to ∞ **beware outliers**
- When averaging we assume measurements are uncorrelated
  - Must modify combination to include correlations (more in a moment)
- Also, averaging measurements that are incompatible with one another makes no sense
  - Two other top mass measurements (175±2) GeV/c<sup>2</sup> and the other with (186±1) GeV/c<sup>2</sup>
  - One (or both) are very likely to be wrong

### **Error propagation**

- On board variance of f=ax+b where a and b are exact constants
  - $\sigma_f = |a| \sigma_x$
- Now in general

$$f(x) = f(x_0) + (x - x_0) \frac{df}{dx}\Big|_{x_0}$$
$$\therefore \sigma_f = \left|\frac{df}{dx}\right| \sigma_x$$

- For 'small errors' when df/dx approximately constant for a few standard deviations about the point.
- If this is not true you have to use a Monte Carlo or a higher order expansion
  - Example next slide: f=exp(-t/ $\tau$ ) with  $\tau$ =(2 ± 0.5) sec and  $\tau$ =(2 ± 0.1) with t = 2 sec

### Error propagation: example



#### $\tau$ =(2 ± 0.5) Propagation Simulation

 $\tau = (2 \pm 0.1)$ 

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## More than one variable and function

- Now we have m different functions  $f_k$  of n different variables  $x_i$  for which there are means and variances  $\mu_i$  and  $\sigma^2_{\ i}$  respectively
  - Note the functions will be correlated even if the variables are not
- The variance of f is given by  $V(f_k) = \langle f_k^2 \rangle \langle f_k \rangle^2$
- Expanding as a Taylor series

$$f_{k}(x_{i}) \approx f_{k}(\mu_{i}) + \sum_{i=1}^{n} \frac{\partial f_{k}}{\partial x_{i}}(x_{i} - \mu_{i})$$
  

$$\Rightarrow V(f_{k}) = \sum_{i=1}^{n} \left(\frac{\partial f_{k}}{\partial x_{i}}\right)^{2} V(x_{i}) + \sum_{i=1}^{n} \sum_{j=1, j \neq i}^{n} \left(\frac{\partial f_{k}}{\partial x_{i}}\right) \left(\frac{\partial f_{k}}{\partial x_{j}}\right) \operatorname{cov}(x_{i}, x_{j})$$
  
and  $\operatorname{cov}(f_{k}, f_{l}) = \sum_{i=1}^{n} \sum_{j=1}^{n} \left(\frac{\partial f_{k}}{\partial x_{i}}\right) \left(\frac{\partial f_{l}}{\partial x_{j}}\right) \operatorname{cov}(x_{i}, x_{j})$ 

## All you need to know about error propagation

- The new covariance can be neatly defined in terms of a matrix multiplication defining m  $\times$  n matrix  ${\bf G}$  as

$$G_{ki} = \frac{\partial f_k}{\partial x_i}$$

- Then
- Where the covariance matrices are n × n for the variables and m × m for the functions.
- Example: f(x,y,z) with x, y, z uncorrelated on board

 $\mathbf{V}_f = \mathbf{G} \ \mathbf{V}_x \ \mathbf{G}^T$ 

### Systematic uncertainties

Those of you doing analysis will one day have to produce a table like this

TABLE II. Summary of the systematic uncertainties for  $R_{Dh}$  and  $A_{Dh}$ . Negligible contributions are denoted by "……"

Source	$R_{DK}$ (%)	$R_{D\pi}$ (%)	$A_{DK}$	$A_{D\pi}$
$\Delta E$ and $C'_{NB}$ PDFs	$^{+6.5}_{-7.1}$	+8.3	+0.03 -0.02	+0.02 -0.03
Fit bias	+0.1	+0.4	•••	•••
Due to $B\bar{B}$ and $q\bar{q}$ bias	$\pm 3.0$	• • •		•••
Peaking background	$\pm 9.5$	$\pm 8.2$	$\pm 0.04$	$\pm 0.01$
Efficiency	$\pm 0.1$	$\pm 0.1$		•••
Detector asymmetry			$\pm 0.02$	$\pm 0.02$
Total	$^{+11.9}_{-12.2}$	$^{+11.7}_{-13.2}$	$\pm 0.05$	$+0.03 \\ -0.04$

[M. Nayak et al., (Belle Collaboration), PRD 88, 091104]

### This analysis is essentially



Ratios are often cool for reducing systematics (why?)

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## Systematic uncertainties: definition

- Take a calorimeter with an energy resolution of 5%
  - measurements are sometimes too high sometimes too low
  - however repeated measurements of the same thing (i.e. mass of  $\pi^0$ ) still leads to a reduced uncertainty
- If it always gives 5% too high it doesn't matter how often you repeat the measurement it will always be off by 5%
  - In reality you have to calibrate this away
- These are systematic uncertainties which are essentially ones that do not scale with 1/sqrt(N)
- Another problem is non-independence at different points
  - For example measuring a differential cross section the luminosity uncertainty moves all points up or down by the same relative amount
- If you ignore these everything looks consistent but your answer is wrong

### Things are not so bad

- Many systematics are easy to deal with:
  - Calibrations, efficiency, luminosities etc which will come with some associated uncertainty which you can propagate
- More problematic are unknowns where some intelligent guesswork is required:
  - Often saved by Gaussian quadrature sum of uncertainties
    - If error is poorly known but small, larger better controlled systematics or your statistical uncertainty will dominate
    - so don't sweat the small stuff just be conservative
- Example of a systematically limited measurement on board
- Barlow's advice is be paranoid about everything and perform checks
  - Fitters on MC samples
  - Divide the data into different periods of data taking
  - Vary analysis procedure
  - Note: these checks do not necessarily lead to systematic uncertainties – only if they throw up a discrepancy

### Systematic uncertainties: look again at our local example

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Total	$^{+11.9}_{-12.2}$	$^{+11.7}_{-13.2}$	$\pm 0.05$	$^{+0.03}_{-0.04}$

[M. Nayak et al., (Belle Collaboration), PRD 88, 091104]

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### Dealing with systematics

- The hard part is the estimation of the systematic uncertainties
- Once you have the errors you can use the covariance matrix in the usual way
- For two measurements  $x_{1,2}$  with common correlated systematic uncertainties S and independent statistical uncertainties  $\sigma_{1,2}$  proof on board

$$\mathbf{V} = \begin{bmatrix} \boldsymbol{\sigma}_1^2 + \boldsymbol{S}^2 & \boldsymbol{S}^2 \\ \boldsymbol{S}^2 & \boldsymbol{\sigma}_2^2 + \boldsymbol{S}^2 \end{bmatrix}$$

• For a common fractional error f it is

$$\mathbf{V} = \begin{bmatrix} \boldsymbol{\sigma}_{1}^{2} + f^{2}x_{1}^{2} & f^{2}x_{1}x_{2} \\ f^{2}x_{1}x_{2} & \boldsymbol{\sigma}_{2}^{2} + f^{2}x_{2}^{2} \end{bmatrix}$$

### Part 3 ESTIMATION

### Properties of estimators

- An estimator is:
  - a procedure applied to the data sample which gives a numerical value for a property of a parent population or, as appropriate a parameter of the parent distribution function
    - Yields, masses, lifetimes, mixing angles or whatever
- Three things we want from an estimator
  - Consistency: the difference between the estimator and the true values vanishes for large samples
  - It is unbiased: the expectation value of the estimator gives the true value
    - Example of mean to show the difference between these statements on the board
  - Efficiency: gives a small variance

### The likelihood function

- Consider some PDF P(x,a) which depends on parameter a which you wish to estimate
- The probability you get a particular set of data x<sub>i</sub> drawn from P(x,a) is

$$L(x_1,...,x_N,a) = \prod_{i=1}^N P(x_i,a)$$

- This is the likelihood function
- If we have an estimator of  $\hat{a}(x_i)$  of our parameter *a* its expectation value is

$$\langle \hat{a} \rangle = \int \hat{a}L \, d\mathbf{x}$$
 where  $d\mathbf{x} \equiv dx_1 dx_2 \dots dx_N$ 

- We will now use this to prove that there is a limit to the efficiency of an estimator
  - The Minimum Variance Bound

### Estimating the variance: Bessel's correction

 Some of you may have seen differing versions of the definition of the standard deviation

$$s = \sqrt{\frac{1}{N-1} \sum_{i} \left(x_i - \overline{x}\right)^2}$$

• Rather than this

$$\sigma = \sqrt{\frac{1}{N} \sum_{i} (x_i - \overline{x})^2}$$

I will now explain the difference – on board

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### Maximum log likelihood

- This is one of the two commonest methods of estimation
  - Simply put you vary the parameter(s) in the likelihood until you find the global maximum
  - In practice one normally solves

$$\frac{d\ln L}{da}\Big|_{a=\hat{a}} = 0$$

- Really you use MINUIT
  - <u>http://seal.web.cern.ch/seal/snapshot/work-packages/mathlibs/minuit/</u> and minimize -2 ln L
    - I will explain the factor 2 in a bit
- But sometimes it can be solved analytically example of the Gaussian weighted mean.

### Max. likelihood is biased...

• On board will show that ML estimate of V is

$$\hat{\sigma}^2 = \frac{1}{N} \sum_{i} \left( x_i - \overline{x} \right)^2$$

which we know is **biased** 

• The reason we use the likelihood is because it is **invariant** under transformations of a – i.e. if we differentiate the Gaussian likelihood we just used with respect to  $\sigma^2$  we get  $\widehat{\sigma^2} = \widehat{\sigma}^2$  - try it yourselves

• In general 
$$\hat{f}(a) = f(\hat{a})$$

### ...but efficient

- We don't worry too much because in the limit of large N a consistent estimator becomes unbiased
- Further the variance of a maximum likelihood estimate lies on the minimum variance bound as N becomes large –
  - proof in Barlow 5.3.3
- Hence, the dominance of L
  - it squeezes the maximum information out of your data
- The pull plot is a useful tool if you are worried about bias in a likelihood fit
  - Recipe: make many simulation experiments (toys)
    - 1. varying sample size generated with some value of your parameter of interest
      - Sample size of toy should be taken from a Poisson distribution with a mean equal to your observed sample size
    - 2. Run your maximum likelihood fit on each of these samples
    - 3. Plot difference between generated and fitted value of parameter divided by the uncertainty on the parameter
    - 4. If distribution is normal ( $\mu$ =0, $\sigma$ =1) even your grumpiest collaborators will be convinced that the fit gives an unbiased estimate with reliable uncertainties

### Uncertainties from the ML

- For large samples one can show (See Barlow Sec. 5.3.3) that L is Gaussian with  $\sigma = \sqrt{V(\hat{a})}$
- Therefore, In L is a parabola which has fallen
  - 0.5 at ±1 sigma from  $\hat{a}$
  - 2 at  $\pm$ 2 sigma from  $\hat{a}$
  - 4.5 at  $\pm$ 3 sigma from  $\hat{a}$
- For small N In L not parabolic but invariance of L means
  - For some alternate parameter a'(a) it is parabolic so still use ln L(max) 0.5 to get  $\pm 1\sigma$
  - Uncertainties in a are asymmetric



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### Least squares

- Suppose you have a set of points {(x<sub>i</sub>,y<sub>i</sub>)}
- $x_i$  are exact, but  $y_i$  have a resolution  $\sigma_i$
- Suppose there is a hypothesis y=f(x;a) and we want to estimate parameter a
- CLT tells us measured y are Gaussian distributed about their true values so

$$P(y_i;a) = \frac{1}{\sigma_i \sqrt{2\pi}} \exp\left[-\left(y_i - f(x_i;a)\right)^2 / 2\sigma_i^2\right]$$
  
$$\Rightarrow \ln L = -\frac{1}{2} \sum \left[\frac{y_i - f(x_i;a)}{\sigma_i}\right]^2 + \text{ constant}$$

Minimise this sum and you maximise ln L method of least squares or  $\chi^2$ 

Can you explain your factor 2 in Minuit now?

### $\chi^2$ fitting binned data Entries/0.2 units

- When you do this
  - myHisto->Fit("gaus");
- Out pops your estimate of the width and mean with an uncertainty
- However, there is an important subtlety here

• 
$$\sigma = \sqrt{N_i}$$

Should be the square root of the integral of the PDF over the bin  $\times$ total number of events

Entries/1 units

- This is the mean of the Poisson distribution from which you assume your event sample is drawn
- Large N no difference but if statistics are small care needs to be taken



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### $\chi^2$ per degree of freedom

- The  $\chi^2$  follows a distribution:
  - proof on board if time allows

$$P(\chi^2, k) = \frac{2^{-k/2}}{\Gamma(k/2)} \chi^{k-2} e^{-\chi^2/2}$$

- Where n = number of degrees
  - = number of data points number of parameters
- Mean is k and variance 2k
- Therefore,  $\chi^2/k\sim 1$  indicates a good fit
  - $\chi^2/k \ll 1$  overestimated the uncertainties
  - $\chi^2/k >> 1$  wrong function or some outlier



Fig. from

### Multi-dimensional Gaussian

Let us consider a set of of variables x={x<sub>1</sub>,x<sub>2</sub>,....,x<sub>n</sub>} with means μ={μ<sub>1</sub>,μ<sub>2</sub>,....,μ<sub>n</sub>} which follow normal distributions with widths σ={σ<sub>1</sub>,σ<sub>2</sub>,....,σ<sub>n</sub>}

$$P(\mathbf{x};\boldsymbol{\mu},\boldsymbol{\sigma}) \propto \exp\left(-\frac{1}{2}(\mathbf{x}-\boldsymbol{\mu})^T \mathbf{A}(\mathbf{x}-\boldsymbol{\mu})\right)$$

- Where A is a n  $\times$  n matrix which depends upon  $\sigma$
- If the variables are **uncorrelated** then **A** is diagonal 1/  $\sigma_i^2$
- If the variables are correlated then matrix is symmetric with

$$\mathbf{A} = \mathbf{V}^{-1}$$

• Section 3.4.6 of Barlow for proof

### $\chi^2$ – generalised

- The multidimensional Gaussian motivates the generalised  $\chi^{\rm 2}$  function

$$\chi^2 = (\mathbf{x} - \mathbf{f})^T \mathbf{V}(\mathbf{x})^{-1} (\mathbf{x} - \mathbf{f})$$

where  $\mathbf{x}=(x_1,...,x_N)$  and  $\mathbf{f}=(f(x_1,\mathbf{a}),...,f(x_1,\mathbf{a})\}$  and the covariance matrix is among the elements of  $\mathbf{x}$ 

• If **f** is linear in **a** then **f=Ca** then you can show that (Barlow 6.6)

$$\mathbf{V}(\mathbf{\hat{a}}) = \left[\mathbf{C}^T \mathbf{V}(\mathbf{x})^{-1} \mathbf{C}\right]^{-1}$$

• If **f** non-linear in **a** then iterate linearly using the Taylor expansion

### Part 4 PROBABILITY AND CONFIDENCE

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### Definition of probability

- Mathematical (Kolmogorov)
  - 1. P>0
  - 2. P(1 or 2) = P(1) + P(2) if 1 and 2 mutually exclusive
  - 3.  $\Sigma P = 1$

Uncontroversial but what is P

- Empirical/Classical (Von Mises) limit of frequency as number of trials/experiments tends to infinity
  - But depends on the ensemble from which all events are chosen
  - Probability of a D meson being produced at sqrt(s)=M(Y(4S)) is different to the probability it is produced in Y(4S) decays
  - What about a single experiment you cannot say anything
- **Objective probability (Popper)** it is a property of an object
  - Does not depend upon ensemble:
    - quantum mechanical probability directly from wavefunction
  - But what about a continuous distribution:  $P(\Delta \theta)$  vs  $P(\Delta \cos \theta)$ ?

### **Bayesian statistics**

- First conditional probability:
  - p(a|b) = probability of a given b
- Bayes theorem
  - p(a|b)p(b) = p(a and b)=p(b|a)p(a)

 $p(a \mid b) = \frac{p(b \mid a) p(a)}{p(b)} = \frac{p(b \mid a) p(a)}{p(b \mid a) p(a) + p(b \mid \overline{a})[1 - p(a)]}$ 

- Example of threshold Cerenkov detector on board
- Now for subjective probability (the controversial piece)

 $p(\text{theory} | \text{result}) = \frac{p(\text{result} | \text{theory})p(\text{theory})}{p(\text{result})}$ 

### Example: spot fixing





What are the chances Sachin or Sreesanth bowl three no-balls in an over?

### Probability – the bottom line

- Subjective probability looks unscientific
- Therefore, we are likely to identify ourselves as frequentists (classical probability) given the problems of objective probability
- But we should not move so fast
  - Certainly in QM most of us think of probabilities as intrinsic objective numbers
  - Interpreting results always leads us into a Bayesian approach: mass of the electron on board
- Philosophical wars rage on the frequentist vs Bayesian approach:
  - My opinion: don't worry about it just always explain clearly what you do when interpreting data and make sure it is consistent
  - If someone wants to interpret your data in a different way it is up to them to explain clearly what they are doing
  - If you do this you are just different not wrong



### Confidence levels - asymmetric

- If the probability distribution is not symmetric there are three possible ways to make your interval
  - 1. Demand a symmetric interval about the mean
  - 2. Make it as small as possible
  - 3. Central interval: have half the remaining probability in each tail
    - Illustrated on board
- Barlow, I and others prefer the latter despite the asymmetry about the mean
  - However, 1 and 2 are not wrong just make sure you have explained what you have done

### **Confidence** in estimation

- Now we want to say something about an unknown parameter
   X given our measurement estimation
- Naively for a measurement of Gaussian errors you measure x with a know  $\sigma$  so you say x–2 $\sigma$  < X < x+2 $\sigma$  at 95% CL
  - As you will see this is often fine but
  - If you measure some branching fraction to be (1±1)% it means from the above approach 16% BF<0!</li>
- Need to use a different approach and that is to build up a confidence belt

### Confidence belt

For example for 90% central interval  $0.05 = \int_{-\infty}^{x_{-}} p(X, x) dx = \int_{x_{+}}^{\infty} p(X, x) dx$ 



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### **Constrained quantities I**

- Now why have I bothered with this
  - What about the case of measuring a negative branching fraction
  - True value 0.1% but you measure (- 0.80±0.41)% means the physical range (0,0.02%) has 95.4% probability if you treat this in a classical way nonsense
  - Bayesian approach
    - P(X|x)=P(x|X)P(X)/P(x)
    - Assumed ignorance of X and the fact that P(x) disappears in the normalization (it is just a scalar number)
    - P(X|x) = P(x|X) which justifies what we did earlier with the mass of the electron
    - Also, frequentist and Gaussian limits are the same

### **Constrained quantities II**

- What about the case of measuring a negative branching fraction
- Bayesian approach
  - P(X | x)=P(x | X)P(X)/P(x)
  - Now for the physical limit  $P(X|x)=P(x|X) \theta(X) / P(x)$  where  $\theta(X)$  is a step function which for a Gaussian distribution function gives

$$p(X \mid x) = \frac{\exp[-(x - X)^2 / 2\sigma^2]}{\int_{0}^{\infty} \exp[-(x - X')^2 / 2\sigma^2] dX'} \quad (x > 0)$$

- Now for my example: BF<0.35% with 90% CL</li>
- But I would of got a different answer if I worked with sqrt(BF)
  - so beware

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### Summary

- We have reviewed
  - 1. Probability distributions
  - 2. Error analysis: including systematics
  - 3. Estimation
  - 4. Setting of confidence intervals
- These lectures contain things which are pretty much the minimum set you should know to be able to critique your own or anyone else's analysis
- One must go on to study things further that are relevant to your particular analysis
- Apologies to those interested in multivariate analysis:
  - I suggest the talks and tutorials from
  - <u>http://tmva.sourceforge.net/</u>